



## Traceability NA TC Chapter Meeting Summary and Minutes

Wednesday, July 19, 2023

4:00-6:00 PM Pacific Time

Online via Web Conference

### TC Chapter Announcements

*Next TC Chapter Meeting*

Wednesday, November 15, 2023

4:00-6:00 PM Pacific Time

Online via Web Conference

### Table 1 Meeting Attendees

*Italics indicate virtual participants*

**Co-Chairs:** Yaw Obeng (NIST), Dave Huntley (PDF Solutions)

**SEMI Staff:** Michelle Sun

<i>Company</i>	<i>Last</i>	<i>First</i>	<i>Company</i>	<i>Last</i>	<i>First</i>
ASML Netherlands BV	<i>Francis</i>	<i>Gregory</i>	PEER Group Inc.	<i>Fuchigami</i>	<i>Albert</i>
Lam Research Corporation	<i>Arrendondo</i>	<i>Manuel</i>	SEMI	<i>Sun</i>	<i>Michelle</i>
NIST - National Institute of Standards & Technology	<i>Pease</i>	<i>Michael</i>	Suny Poly	<i>Eisenbraun</i>	<i>Eric</i>
Omron Automation Americas	<i>Deeb</i>	<i>Joseph</i>	X-FAB Sarawak Sdn. Bhd	<i>Liew</i>	<i>Emily</i>

### Table 2 Leadership Changes

<i>WG/TF/SC/TC Name</i>	<i>Previous Leader</i>	<i>New Leader</i>
License Server Certification Task Force [New]		Sashi Subramanian (Cadence)

### Table 3 Committee Structure Changes

<i>Previous WG/TF/SC Name</i>	<i>New WG/TF/SC Name or Status Change</i>
	License Server Certification Task Force [New]

### Table 4 Ballot Results

<i>Document #</i>	<i>Document Title</i>	<i>Committee Action</i>
7060	Reapproval of SEMI T17-0706 (Reapproved 0718), Specification of Substrate Traceability	<b>Passed</b>
7061	Reapproval of SEMI T10-0701 (Reapproved 0618), Test Method for the Assessment of 2D Data Matrix Direct Mark Quality	<b>Passed</b>



**Table 4 Ballot Results**

<i>Document #</i>	<i>Document Title</i>	<i>Committee Action</i>
7062	Reapproval of SEMI T18-1106 (Reapproved 0718), Specification of Parts and Components Traceability	<b>Failed</b>

#1 **Passed** ballots and line items will be submitted to the ISC Audit & Review Subcommittee for procedural review.

#2 **Failed** ballots and line items were returned to the originating task forces for re-work and re-balloting or abandoning.

**Table 5 Activities Approved by the GCS between meetings of the TC Chapter**

<i>#</i>	<i>Type</i>	<i>SC/TF/WG</i>	<i>Details</i>
None			

**Table 6 Authorized Activities**

Listing of all revised or new SNARF(s) approved by the Originating TC Chapter.

<i>#</i>	<i>Type</i>	<i>SC/TF/WG</i>	<i>Details</i>
None			

#1 SNARFs and TFOFs are available for review on the SEMI Web site at:

<http://downloads.semi.org/web/wstdsbal.nsf/TFOFSNARF>

**Table 7 Authorized Ballots**

<i>#</i>	<i>When</i>	<i>TF</i>	<i>Details</i>
7136	Cycle 7-2023	5-Year Review TF	Reapproval of SEMI T3-1213 (Reapproved 0419), Specification for Wafer Box Labels

**Table 8 SNARF(s) Granted a One-Year Extension**

<i>#</i>	<i>TF</i>	<i>Title</i>	<i>Expiration Date</i>
None			

**Table 9 SNARF(s) Abolished**

<i>#</i>	<i>TF</i>	<i>Title</i>
None		

**Table 10 Standard(s) to receive Inactive Status**

<i>Standard Designation</i>	<i>Title</i>
SEMI T18-1106 (Reapproved 0718)	Specification of Parts and Components Traceability

**Table 11 New Action Items**

<i>Item #</i>	<i>Assigned to</i>	<i>Details</i>
None		



**Table 12 Previous Meeting Action Items**

<i>Item #</i>	<i>Assigned to</i>	<i>Details</i>
None		

**1 Welcome, Reminders, and Introductions**

Albert Fuchigami (PEER Group) called the meeting to order at 4:05. The meeting reminders on antitrust issues, intellectual property issues and holding meetings with international attendance were reviewed. Attendees introduced themselves.

**Attachment:** Required Meeting Elements Nov 2022

**2 Review of Previous Meeting Minutes**

The TC Chapter reviewed the minutes of the previous meeting.

- Motion:** Approve the minutes as written
- By / 2<sup>nd</sup>:** By: Eric Eisenbraun / suny poly  
Second: Nick Infelise / Omron Electronics, Inc
- Discussion:** None
- Vote:** 6-Y 0-N

**Attachment:** Trace-TC-Chapter-Minutes-April-2023

**3 Liaison Reports**

*3.1 SEMI Staff Report*

Michelle Sun (SEMI) gave the SEMI Staff Report. Of note:

2023 Calendar of Events

- SEMICON West
  - o July 11-13
  - o San Francisco, CA
- SEMICON Taiwan
  - o Sept 6-8
  - o Taipei, Taiwan
- SEMICON Europa
  - o Nov 14-17
  - o Munich, Germany
- SEMICON Japan
  - o Dec 13-15
  - o Tokyo, Japan

Upcoming NA Meetings

- NA Standards Fall Meetings
  - o Nov 6-9, 2023
  - o SEMI HQ, Milpitas, CA
- NA Standards Spring Meetings
  - o April 1-4, 2024
  - o SEMI HQ, Milpitas, CA
- SEMICON West
  - o July 2024



- o Moscone Center, San Francisco

Critical Dates

2023	Ballot Submission Deadline	Voting Opens	Voting Closes
Cycle 6	July 26	August 9	September 8
Cycle 7	August 30	September 13	October 13
Cycle 8	October 4	October 18	November 17
Cycle 9	November 15	November 29	December 29

New Publications Staff

- Vivian Hoang – Sr. Specialist, Standards Publications
  - o Joined SEMI May 17, 2023.
  - o Will focus on processing ballots to reduce backlog and improve publishing time.

SEMI Standards Publications

- Total SEMI Standards in portfolio: 1,079
- Includes 327 Inactive Standards

Cycle	New	Revised	Reapproved	Withdrawn
March 2023	2	2	0	0
April 2023	1	10	4	0
May 2023	0	4	2	0
June 2023	1	10	7	0

New Standards

Cycle	Designation	Title	Committee	Region
March 2023	SEMI FH1	Test Method of Line Impedance for Electronic Textiles	Flexible Hybrid Electronics	TW
March 2023	SEMI FH2	Test Method of Sheet Resistance for Woven Electronic Textiles	Flexible Hybrid Electronics	TW
April 2023	SEMI M92	Specification for 4H-SiC Homoepitaxial Wafer	Compound Semiconductor Materials	CH
June 2023	SEMI PV100	Test Method of Wind Uplift Resistance for Photovoltaic Modules Roof (BIPV)	Photovoltaic	CH

Five-Year Review

- SEMI T3-1213 (Reapproved 0419) - Specification for Wafer Box Labels

Standards Awards

- Emily Liew (X-Fab) was awarded the 2023 Corporate Device Member Award at SEMICON West for her contribution to the revisions of SEMI M12 and M13.

**Attachment:** Staff Report July 2023 v3



## 4 Ballot Review

NOTE 1: TC Chapter adjudication on ballots reviewed is detailed in the Audits & Review (A&R) Subcommittee Forms for procedural review. The A&R forms are available as attachments to these minutes. The attachment number for each balloted document is provided under each ballot review section below.

### 4.1 Document #7060, Reapproval of SEMI T17-0706 (Reapproved 0718), Specification of Substrate Traceability

**Motion:** This is not a Safety Document, when all safety-related information is removed, the Document is still technically sound and complete. (Regulations ¶ 8.7.1)

**By / 2<sup>nd</sup>:** By: Eric Eisenbraun / suny poly  
Second: Nick Infelise / Omron Electronics, Inc

**Discussion:** None

**Vote:** 5 Y-0 N; Motion passed

**Motion:** This Document passed TC Chapter review as balloted and will be forwarded to the ISC A&R SC for procedural review.

**By / 2<sup>nd</sup>:** By: Nick Infelise / Omron Electronics, Inc  
Second: Eric Eisenbraun / suny poly

**Discussion:** None

**Vote:** 7 Y-0 N; Motion passed

**Attachment:** AR - 7060

### 4.2 Document #7061, Reapproval of SEMI T10-0701 (Reapproved 0618), Test Method for the Assessment of 2D Data Matrix Direct Mark Quality

**Motion:** This is not a Safety Document, when all safety-related information is removed, the Document is still technically sound and complete. (Regulations ¶ 8.7.1)

**By / 2<sup>nd</sup>:** By: Nick Infelise / Omron Electronics, Inc  
Second: Eric Eisenbraun / suny poly

**Discussion:** None

**Vote:** 5 Y-0 N; Motion passed

**Motion:** This Document passed TC Chapter review as balloted and will be forwarded to the ISC A&R SC for procedural review.

**By / 2<sup>nd</sup>:** By: Nick Infelise / Omron Electronics, Inc  
Second: Manuel Arrendondo / Lam Research Corporation

**Discussion:** None

**Vote:** 7 Y-0 N; Motion passed

**Attachment:** AR - 7061

### 4.3 Document #7062, Reapproval of SEMI T18-1106 (Reapproved 0718), Specification of Parts and Components Traceability

**Motion:** Negative is related and persuasive.

**Reason:** Voters feel that the standard is invalid because it is inappropriate to define lifetime due to variable use cases by each end user. Therefore the document should not be reapproved.

**By / 2<sup>nd</sup>:** By: Manuel Arrendondo / Lam Research Corporation  
Second: Eric Eisenbraun / suny poly

**Discussion:** None



**Vote:** 3 Y-0 N; Motion passed

**Motion:** This Document failed TC Chapter review and work will be discontinued.

**By / 2<sup>nd</sup>:** By: Manuel Arrendondo / Lam Research Corporation  
Second: Eric Eisenbraun / suny poly

**Discussion:** Intention is for Standard to go Inactive.

**Vote:** 5 Y-0 N; Motion passed

### 5 Next Meeting and Adjournment

The next meeting is scheduled for Wednesday, November 15, 2023, via Web Conference. See <http://www.semi.org/standards-events> for the current list of events.

Adjournment: 5:30.

Respectfully submitted by:

Michelle Sun

Coordinator

SEMI North America

Phone: 408.943.7982

Email: [msun@semi.org](mailto:msun@semi.org)

Minutes tentatively approved by:

Yaw Obeng (NIST), Co-chair	10/12/2023
Dave Huntley (PDF Solutions), Co-chair	10/12/2023

**Table 13 Index of Available Attachments<sup>#1</sup>**

<i>Title</i>	<i>Title</i>
Required Meeting Elements Nov 2022	AR - 7060
Trace-TC-Chapter-Minutes-April-2023	AR - 7061
Staff Report July 2023 v3	

#1 Due to file size and delivery issues, attachments must be downloaded separately. A .zip file containing all attachments for these minutes is available at [www.semi.org](http://www.semi.org). For additional information or to obtain individual attachments, please contact [SEMI Staff Name] at the contact information above.